

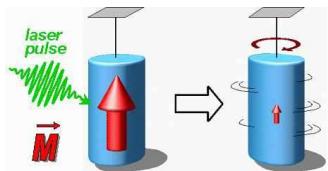
Parallel fs X-Ray Spectrometer

A. Erko, A. Firsov, K. Holldack

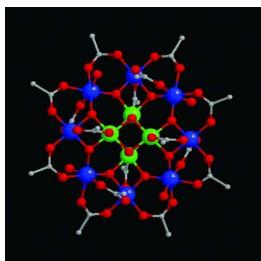
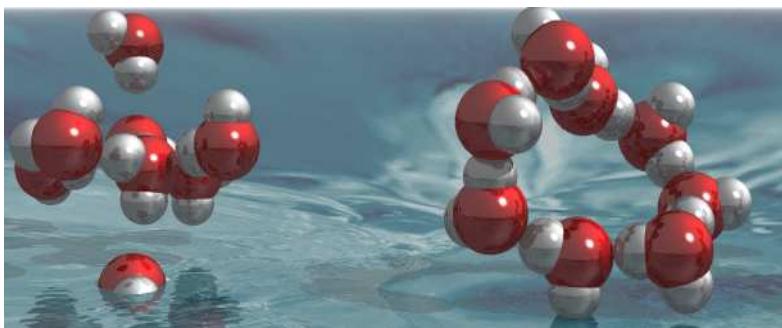
*Helmholtz-Zentrum Berlin für Materialien und Energie GmbH
Elektronenspeicherring BESSY II, Albert-Einstein-Str. 15, 12489 Berlin*



Motivation



4.91	62	Sm	150.36	63	Eu	151.97	64	Gd	157.25	65	Tb	158.93	66	Dy	162.50	67	Ho	164.93	68	Er	167.26	69	T
7.738	7.538	Samarium	179.4	5.243	Europium	142.9	8.26	180.4	8.251	13.12	177.3	8.251	13.12	8.559	8.407	8.795	1.474	9.062	1.497	9.325	5	Tb	



Ultrafast transfer of angular momentum between spins and lattice in ferromagnetic materials

Femtochemistry:
Understanding the dynamics and formation of a chemical bond by time resolved electron spectroscopy, at surfaces, in molecules, and clusters

Spindynamik:
Molekular magnets und thin-layer solar cells

„Free electron“ light sources

Courtesy J. Feldhaus



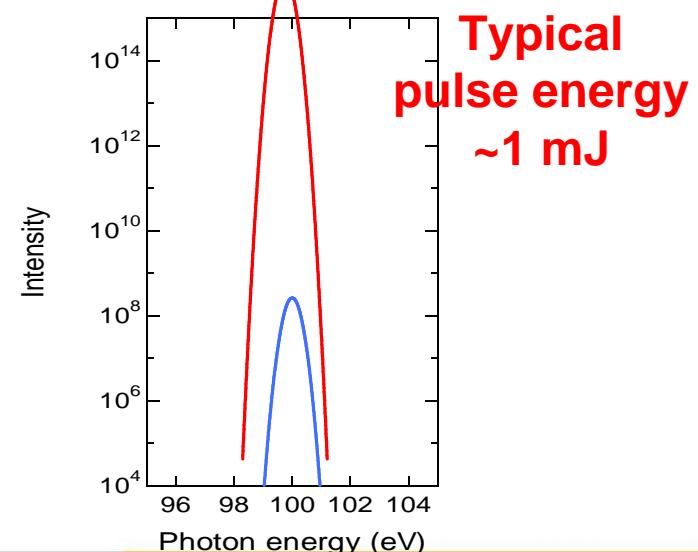
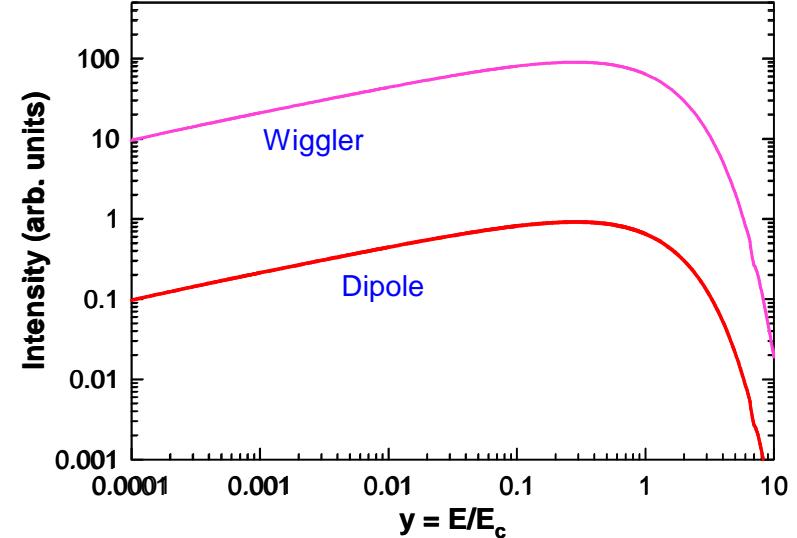
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Dipole magnet
Synchrotron radiation

Wiggler

Undulator

FEL



Time-resolved experiments at BESSY II

Single – bunch mode:

~ 50 picosecond, 20 mA, 10^9 – 10^{13} ph/sec, 10 eV – 150 keV

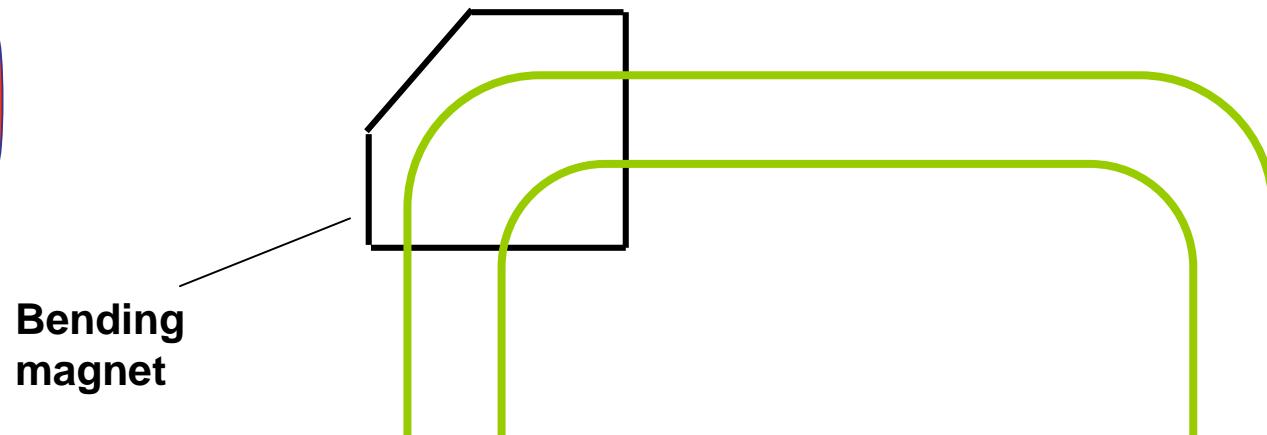
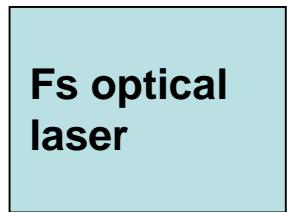
α – mode :

~ 1-10 picosecond, 2 mA, 10^6 – 10^8 ph/sec, 10 eV – 15 keV

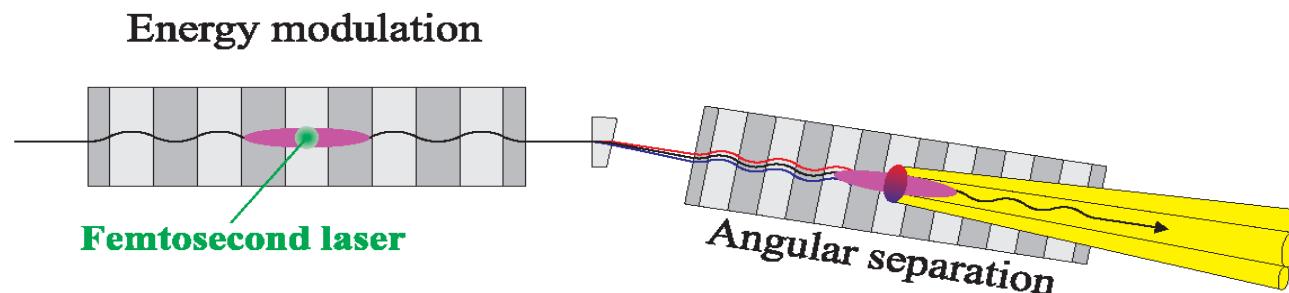
Slicing undulator:

**~ 0.1 picosecond, 10^7 - 10^8 ph/sec, 300 eV – 1200 eV in 5% BW
(10-100 ph/pulse)**

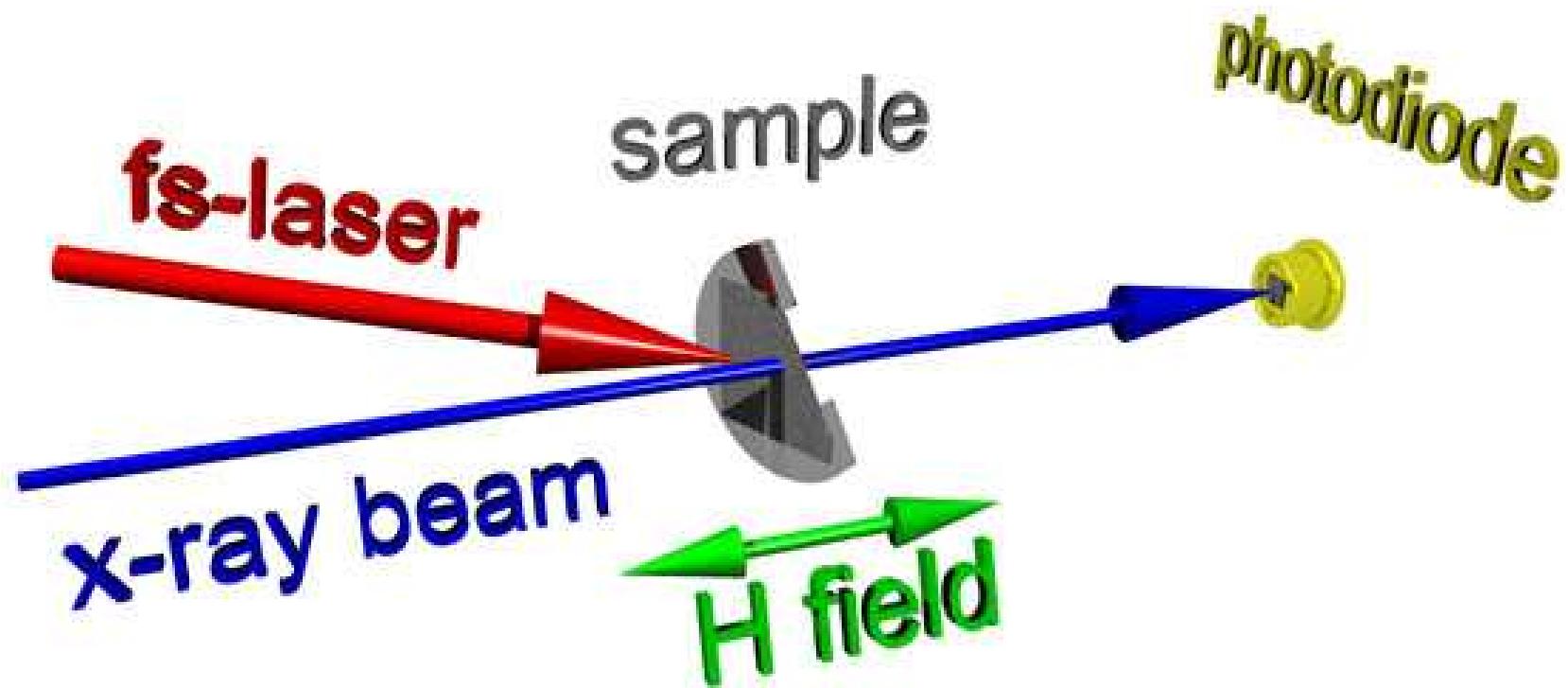
Principle of the „photon slicing“ method



- ALS pioneered fs slicing with signal : background ~ 1:1
- BESSY pioneered angular separation scheme with signal : background >10:1
- SLS (2006) and SOLEIL (~2008) will implement angular separation



Pump-probe experimental setup

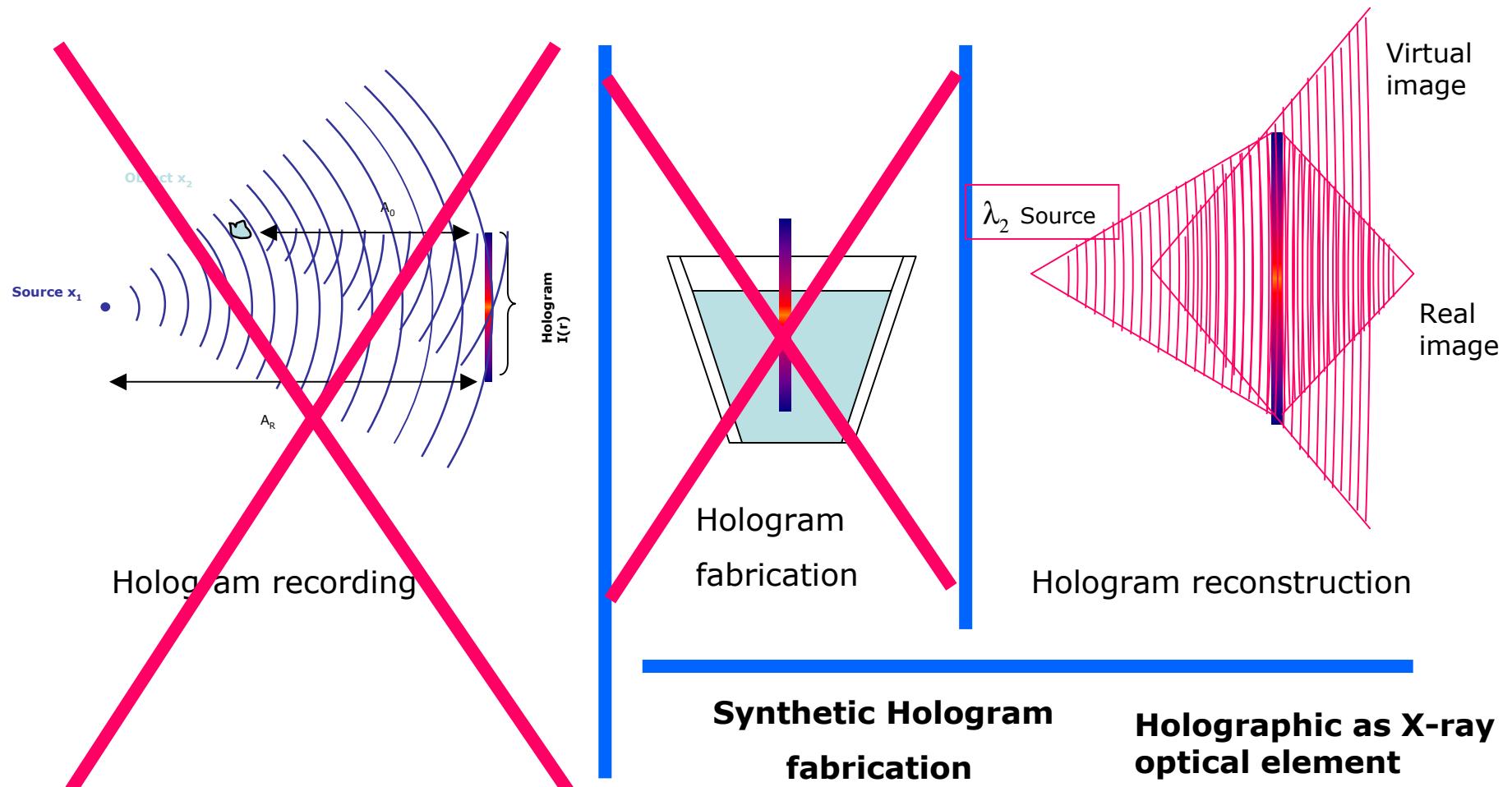




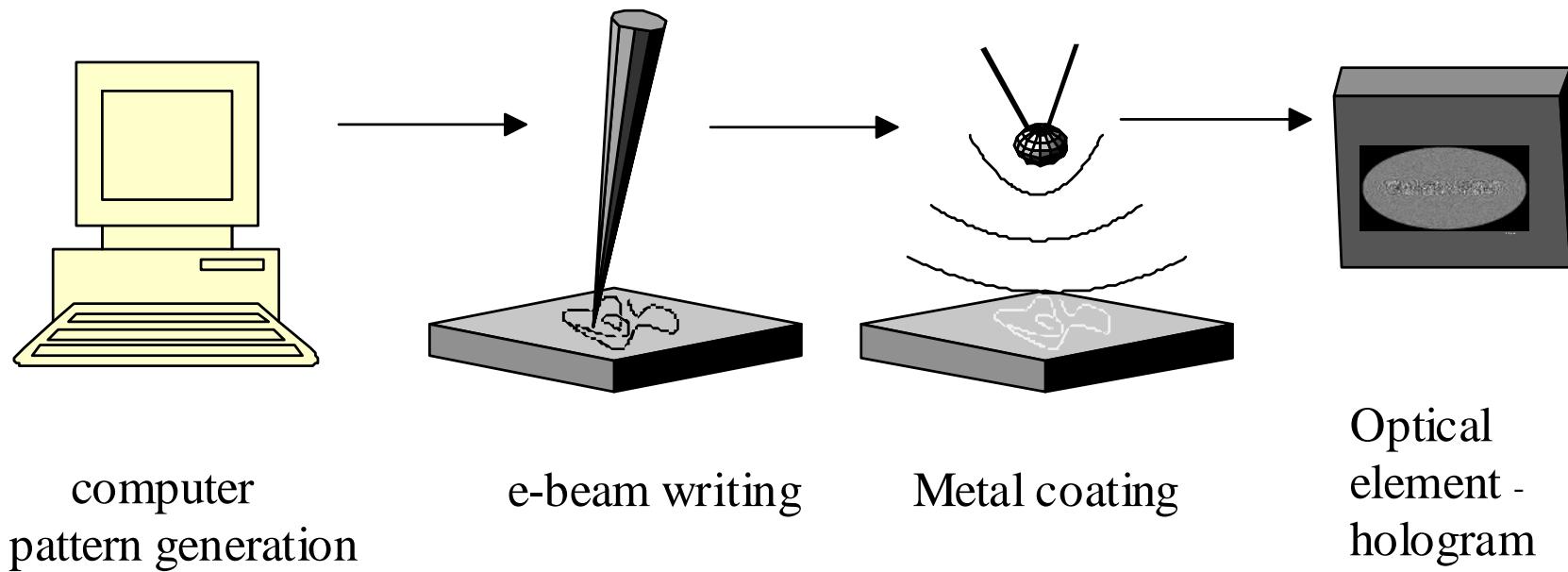
- Time delay in optics < 30 fs
- Maximum possible efficiency
- Parallel spectral measurements
- Bremsstrahlung blocking

Optical element must combine:
Reflection + focusing + dispersion

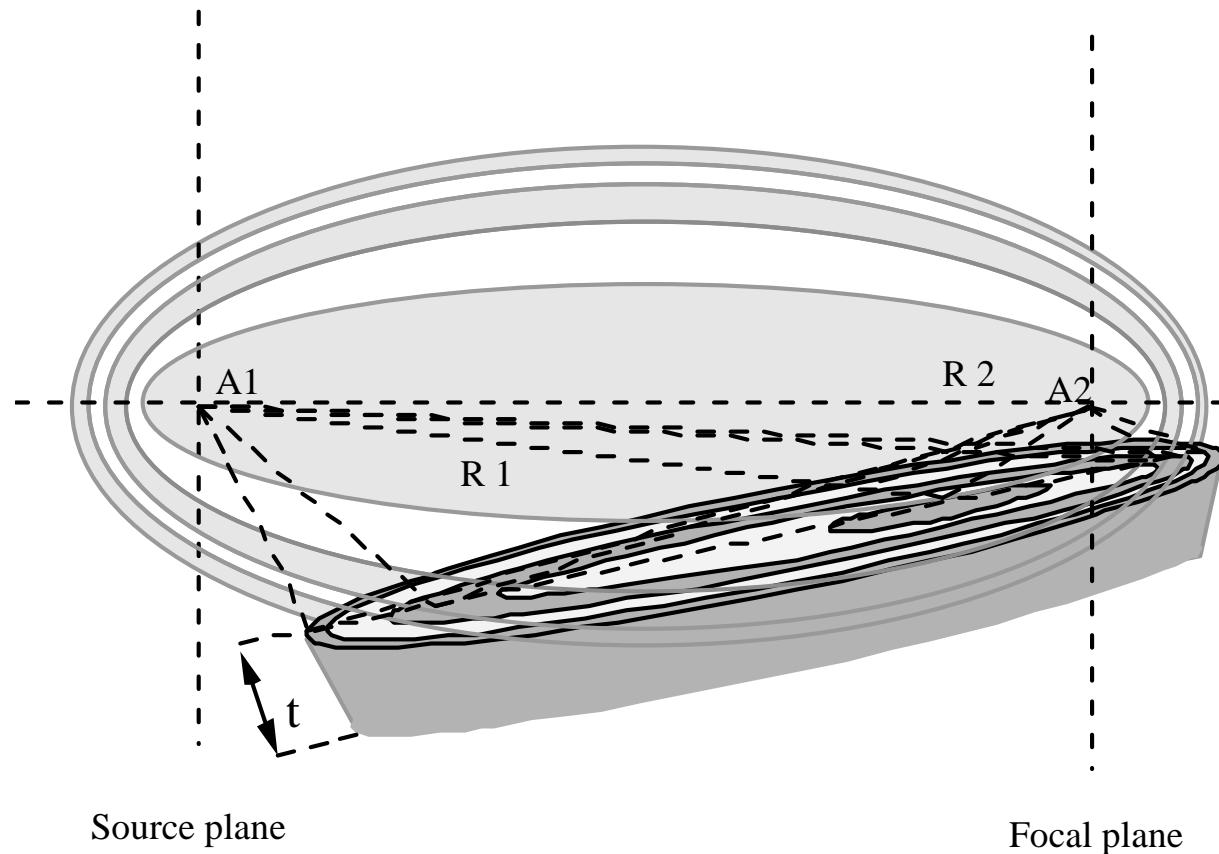
The main principle: Holographic process



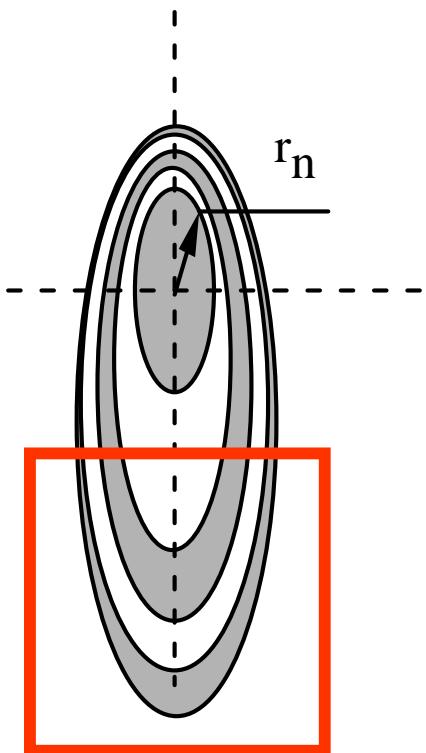
Computer generated holographic optics



Elliptical Reflection zone plate (RZP)



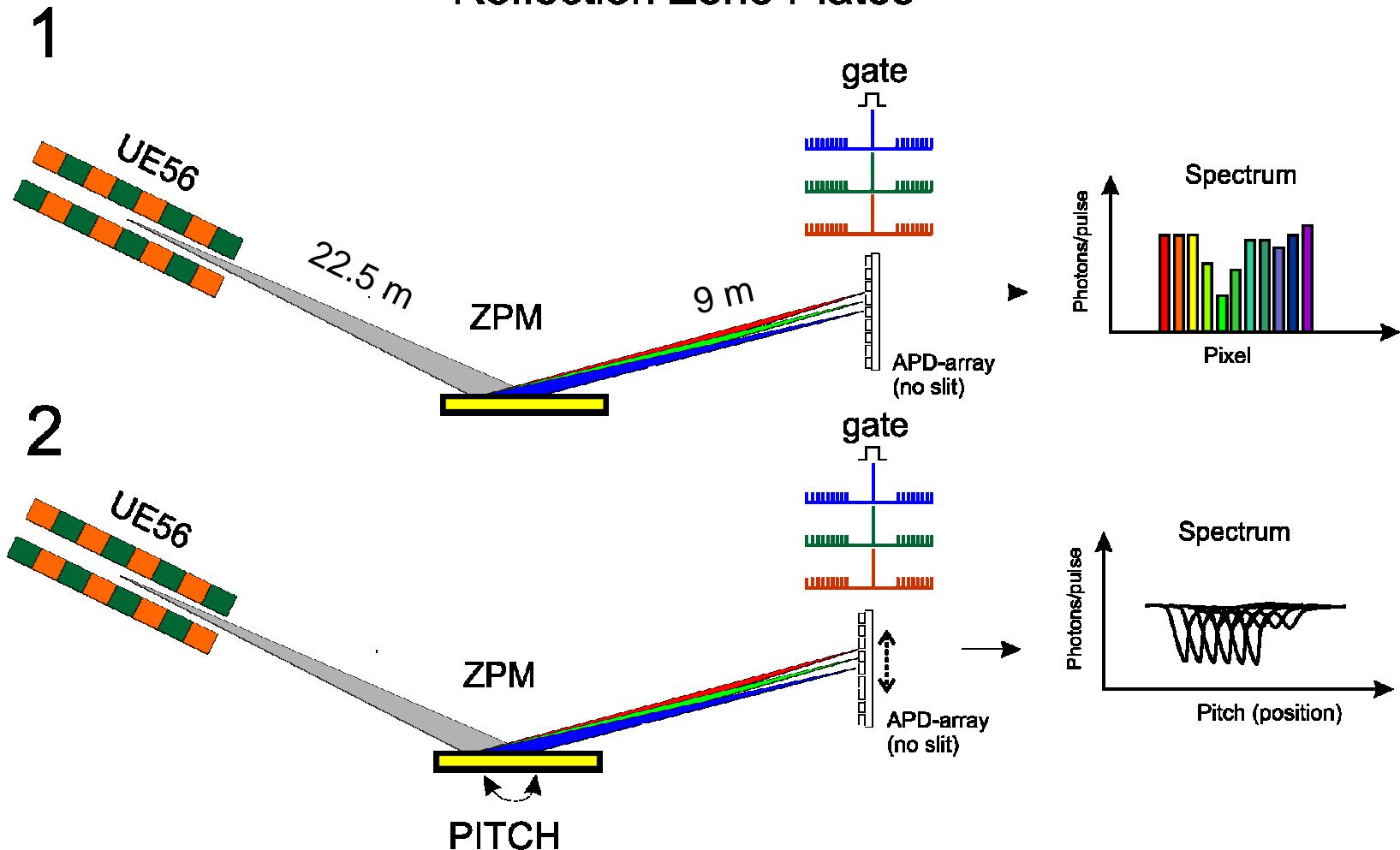
Cross-section of
Off - axes ZP



Off-axis part of RZP



Time-Correlated Parallel detection with Reflection Zone Plates



Time resolution requirements

Requirements: the time delay in the optical element **< 30 fs.**

The number of periods in the diffraction structure:

$$N_{\max} = \frac{\Delta t_{pulse}}{\Delta t_\lambda}$$

where $\Delta t_{pulse} = 3 \cdot 10^{-14}$ is the X-ray pulse duration

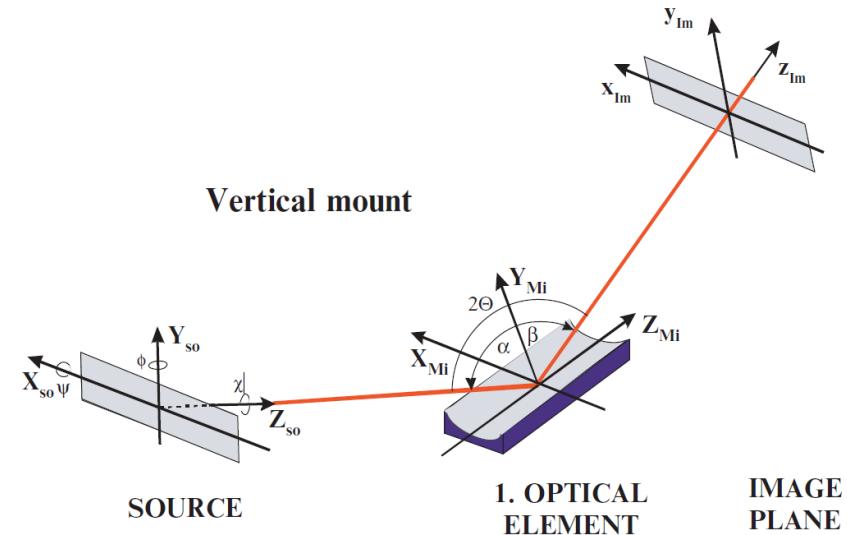
$$\Delta t_\lambda = \frac{\lambda_{Fe}}{c} \approx 0.578 \cdot 10^{-17} s$$
 is the time delay for the Fe L-edge radiation (~ 710 eV)

The maximum number of grooves is **N_{max} < 5200.**

Maximum length of the optical element is **80 mm**

- Simulate Optical systems up to 10 elements
- Beamline design tool
- Geometric Optics
- Sources
 - Point
 - Dipole
 - Undulator
- Optical elements
 - Reflection Mirrors
 - Crystals (graded)
 - Gratings (VLS)
 - Transmission Zone Plates (cooperation Prague Uni. COST 2004 supported)
 - Reflection Zone plates (cooperation King's College London COST 2008 supported)

COORDINATE SYSTEM OF RAY



Vertical mount

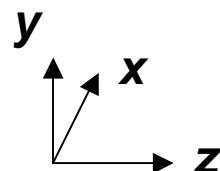
A. Erko, COST MP0601 Meeting, Krakow, 27.05.2010

The main calculation principle

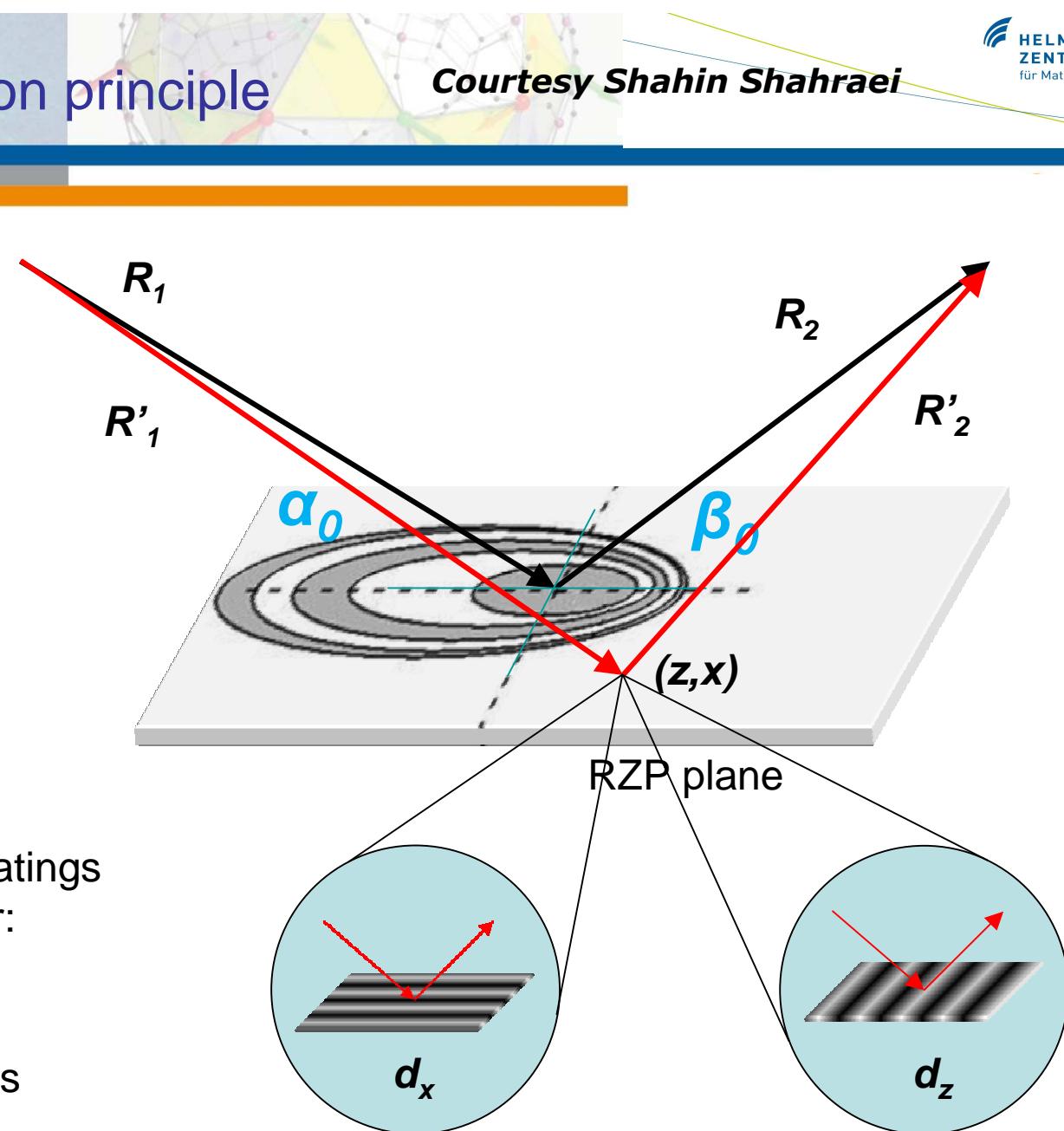
Courtesy Shahin Shahraei

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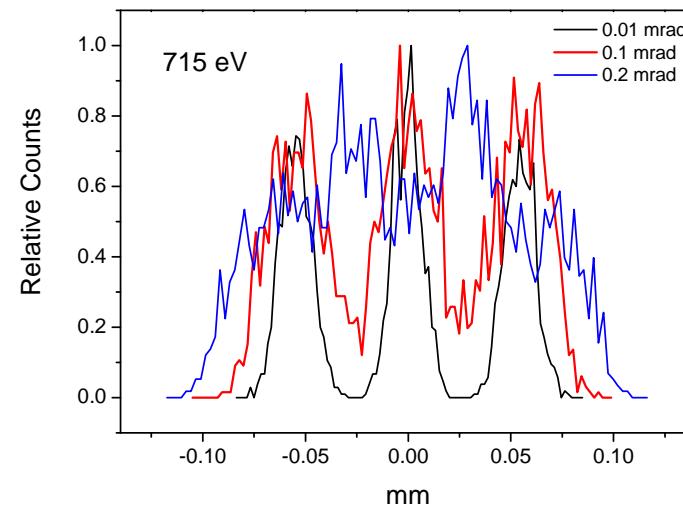
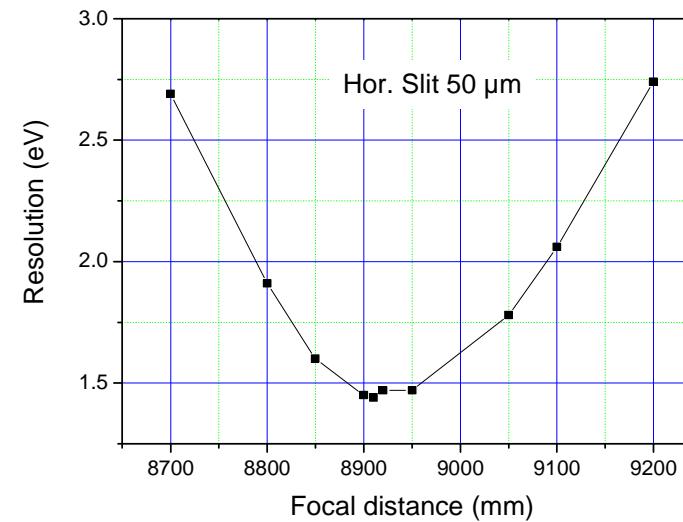
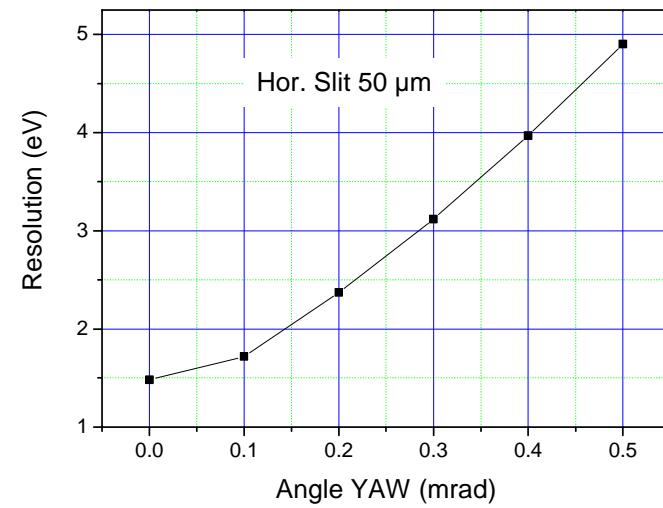
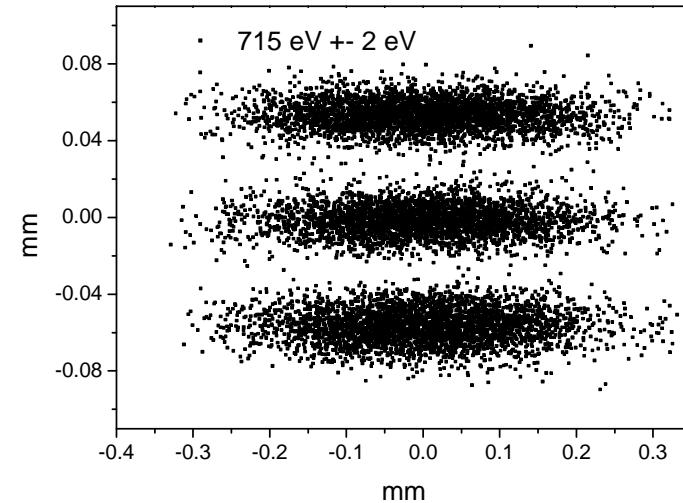
Raytracing
code RAY for
fs beamline
calculation



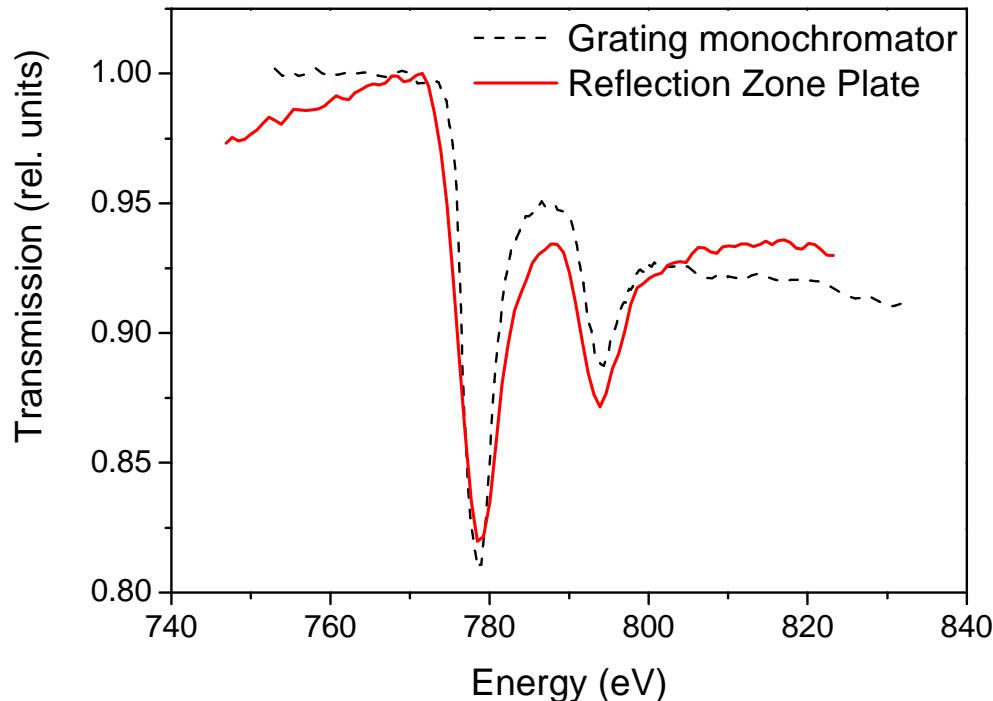
- Superposition of gratings
- Local grating vector:
 - d_x
 - d_z
- Decreases outwards



Raytracing code application: fs RZP focal plane

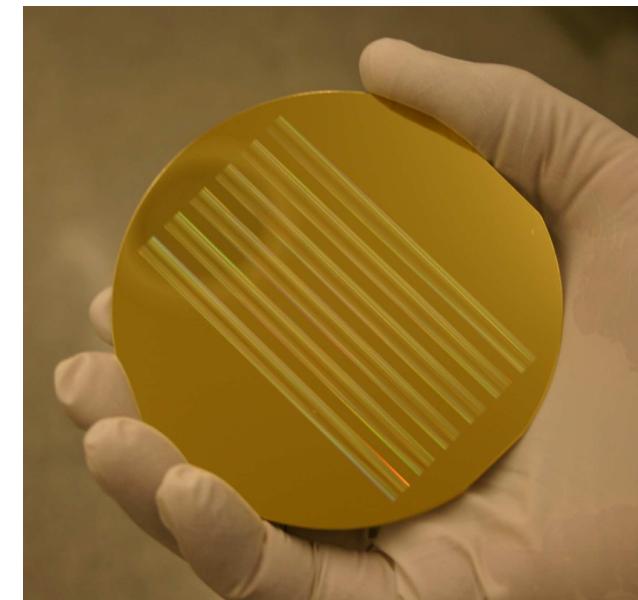


Combination on the same optical element the reflection, focusing and dispersion.



Absorption spectrum of Co foil 40 nm thick

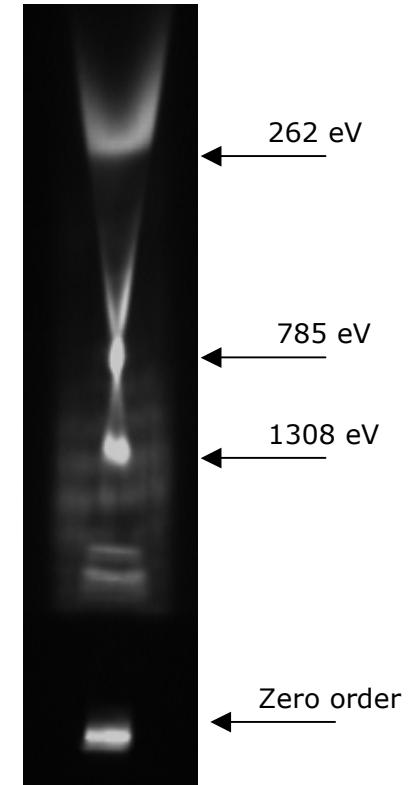
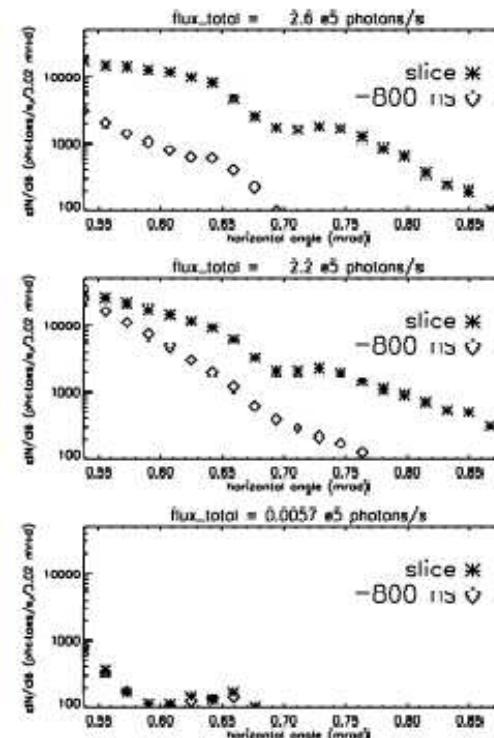
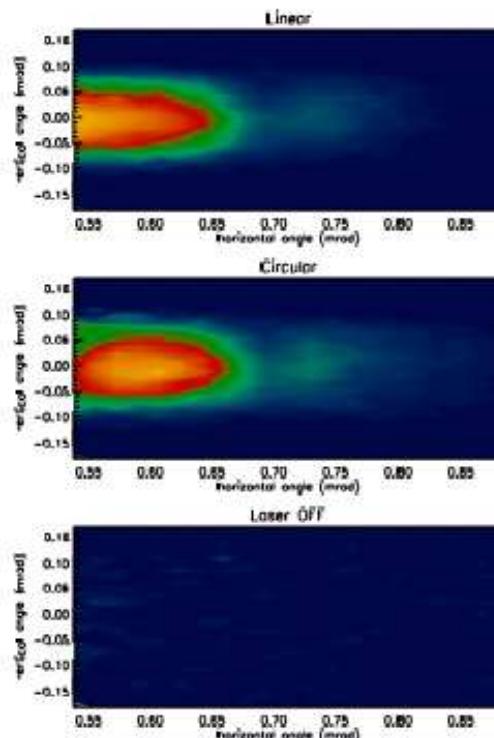
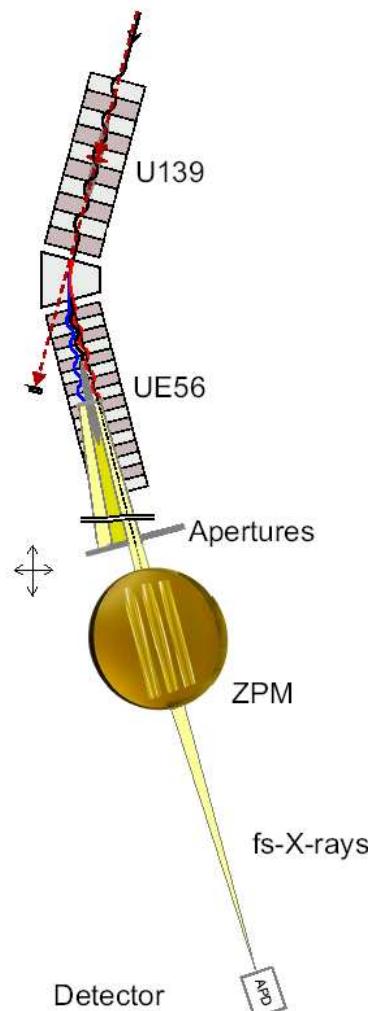
The flux is 10 times higher as grating monocromator



Gold reflection off-axis zone plates on a Si substrate: Focal distance: 902 cm. Outer zone: 1 μm. Aperture: 80 mm x 10 mm

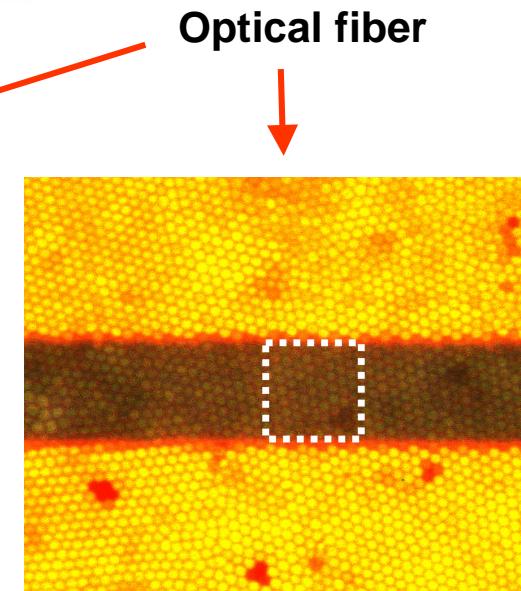
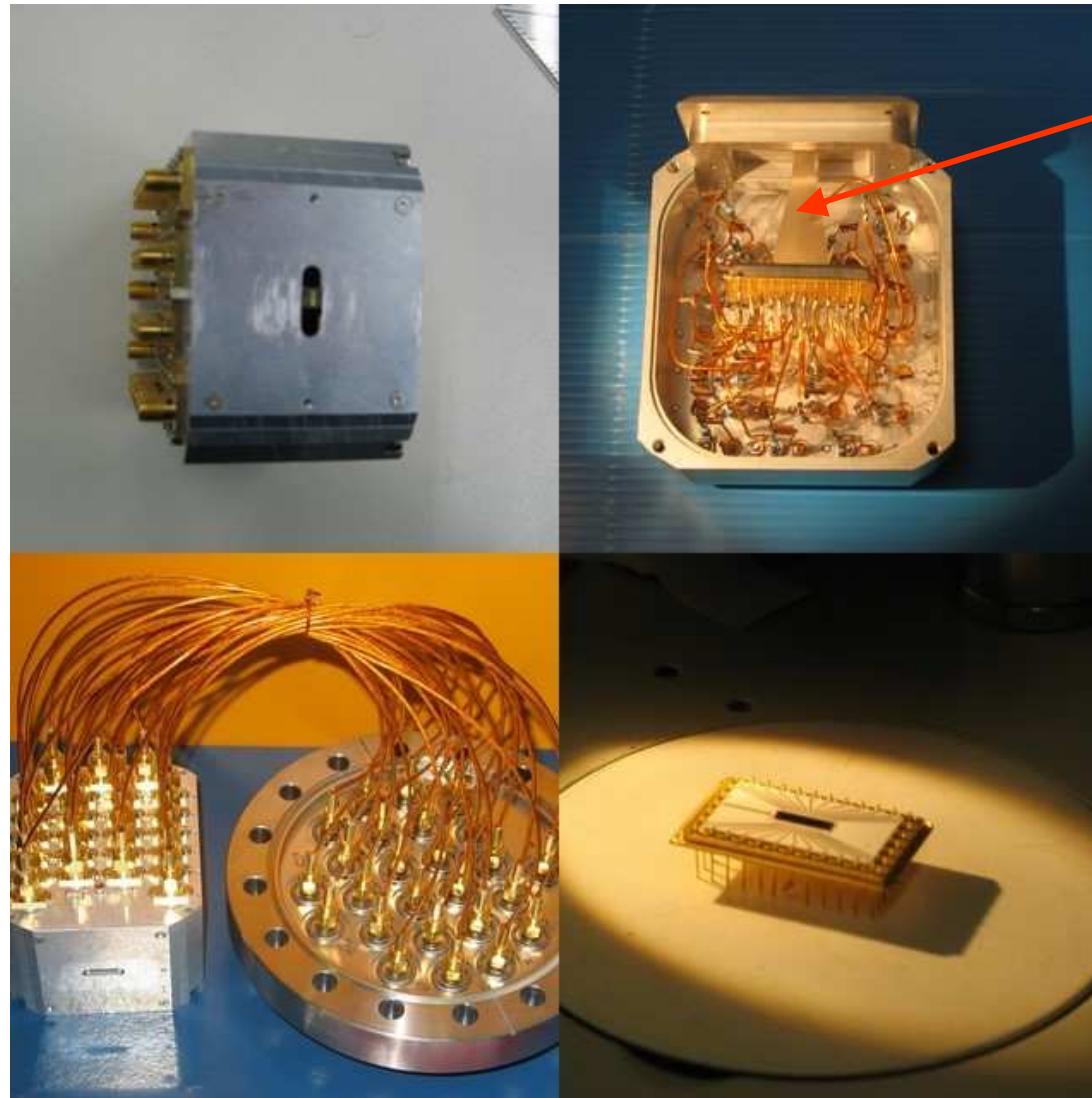
Lenses groove depth is 8 nm.

Reflection Zone Plates map sliced photons



Beamline optics focal spot: ~ 300 µm (H) x 25 µm (V)
Energy dispersion in focal plane: ~ 40 eV / mm
Total beamline optics transmittance: ~ 6.5%
Time resolution of beamline optics: ~ 30 fsec

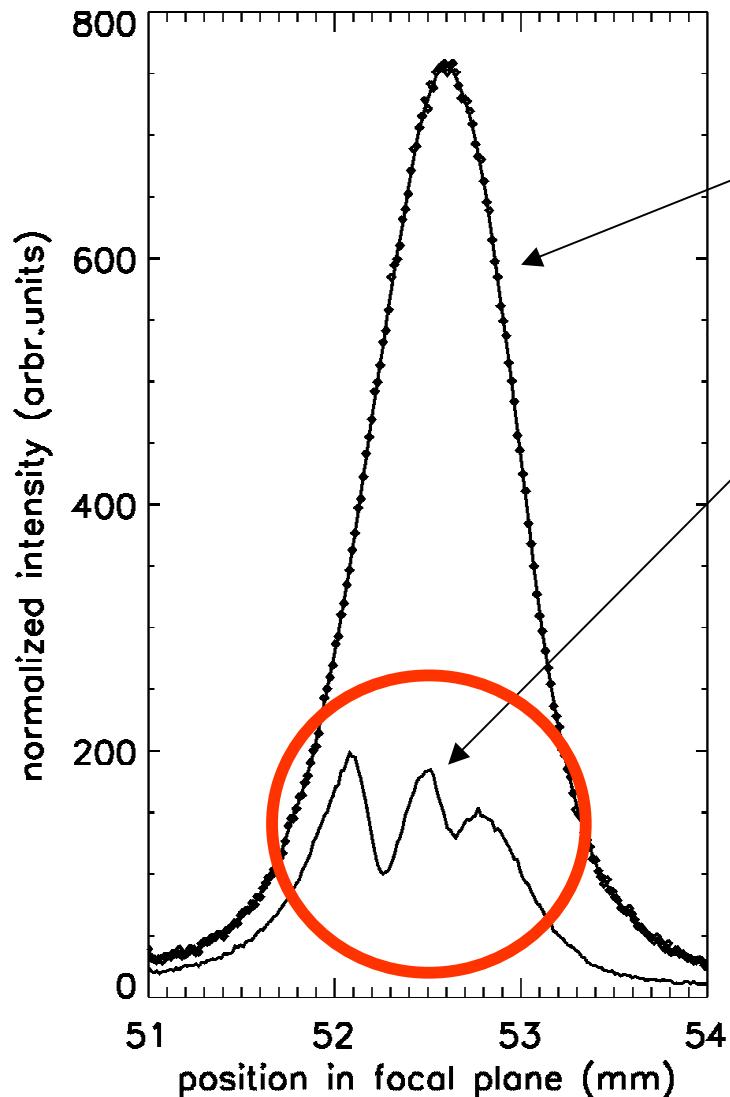
Parallel detector for fs beamline



Optical fiber

Parallel detector array consists of 25 avalanche diodes, $300 \times 300 \mu\text{m}^2$ each. Optical fiber is used to improve resolution down to $50 \times 50 \mu\text{m}^2$.

XANES with fs time resolution

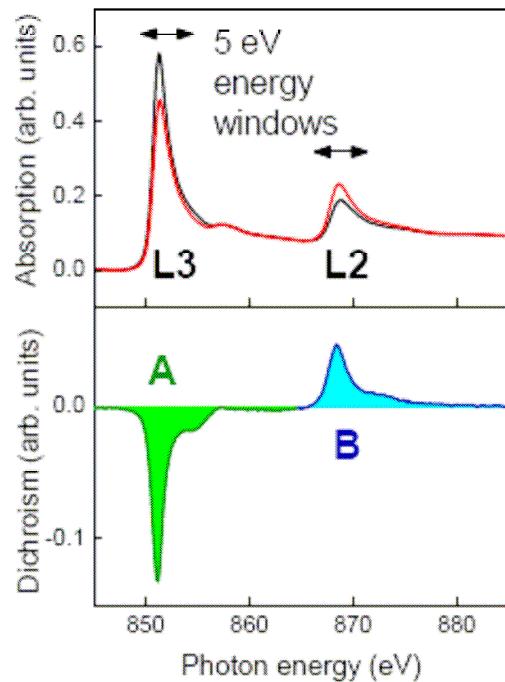


Transmission spectra from a 30 nm Ni thin film. A single-pixel APD-signal, being gated on the hybrid-bunch, while the detector was moved along the dispersion plane. The 3rd harmonics from the UE56 with (dots) and without the Ni-foil (line) in the beam path.

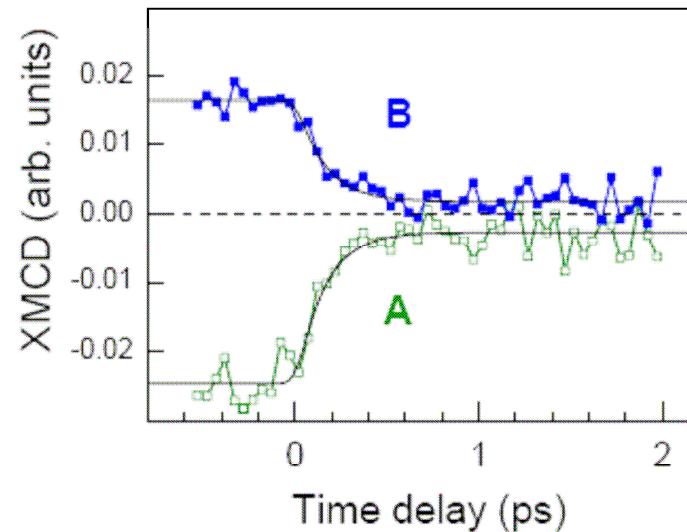
Time-Resolved XMCD on Ni film

Courtesy C. Stamm

Ni dichroism spectrum
(equilibrium, high resolution)



fs time-resolved dichroism
(energy window \approx 5 eV)



$$\tau = 150 \pm 50 \text{ fs}$$

fit with exponential decay
(same for A, B)

Parallel X-ray Diffraction Spectrometer (DiS)

Detector array

DiS-element

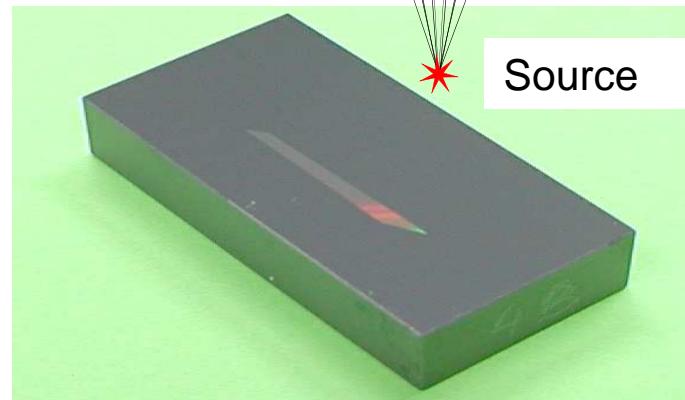
Array detector

Off-axis Reflection Zone Plate with variable
Coating: Au on Si substrate

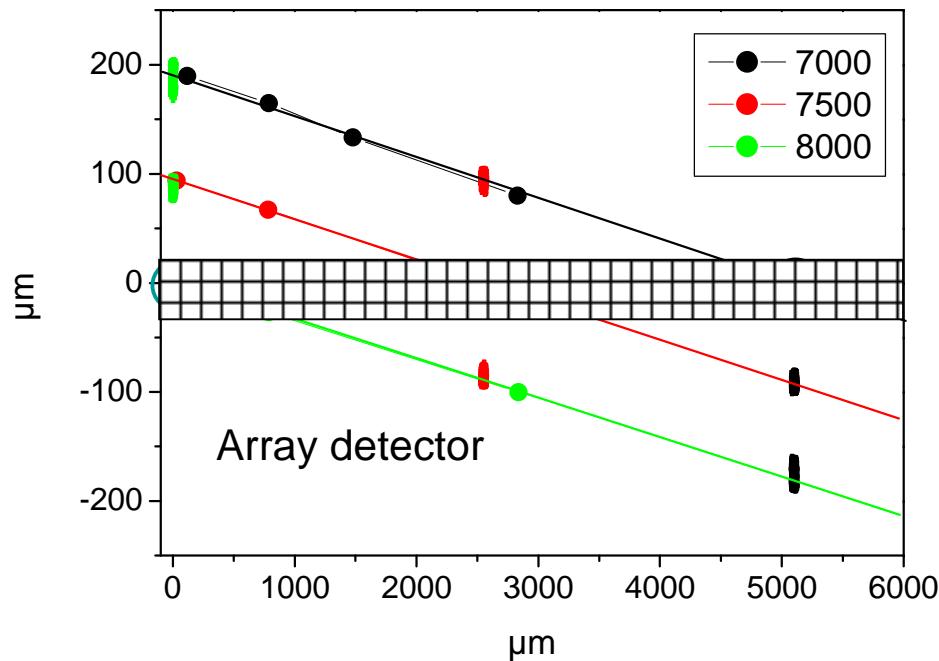
Reflection
zone plate
DiS prototype (HZB)

Source

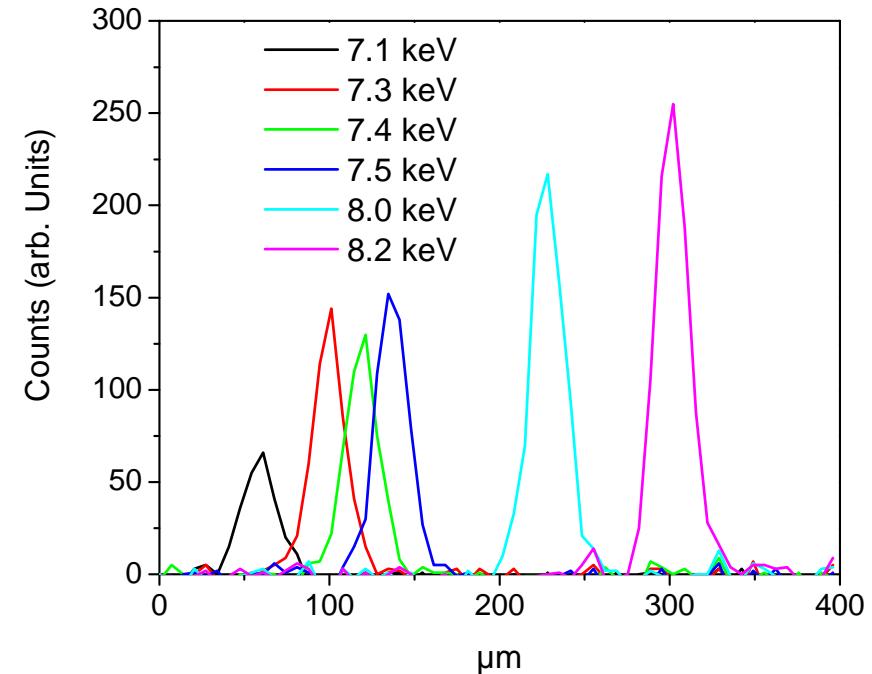
Total external reflection structure
(High-Energy DiS)



DiS tests in the energy range of 7100 eV – 8200 eV



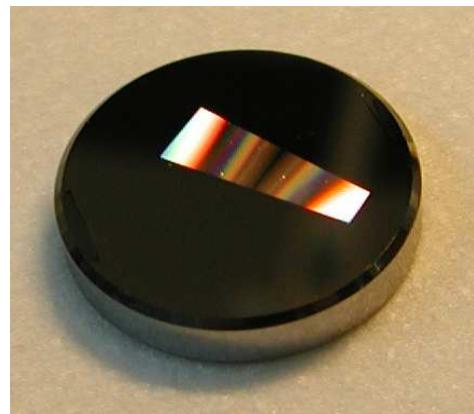
The dispersion of the parallel diffraction spectrometer DiS for the energy range between 6 and 8 keV.



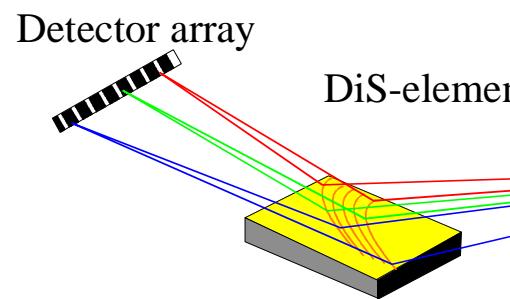
Resolution test of a parallel diffraction spectrometer (DiS) element for the energy range between 6 and 8 keV

Nano-focusing with capillary micro-lens

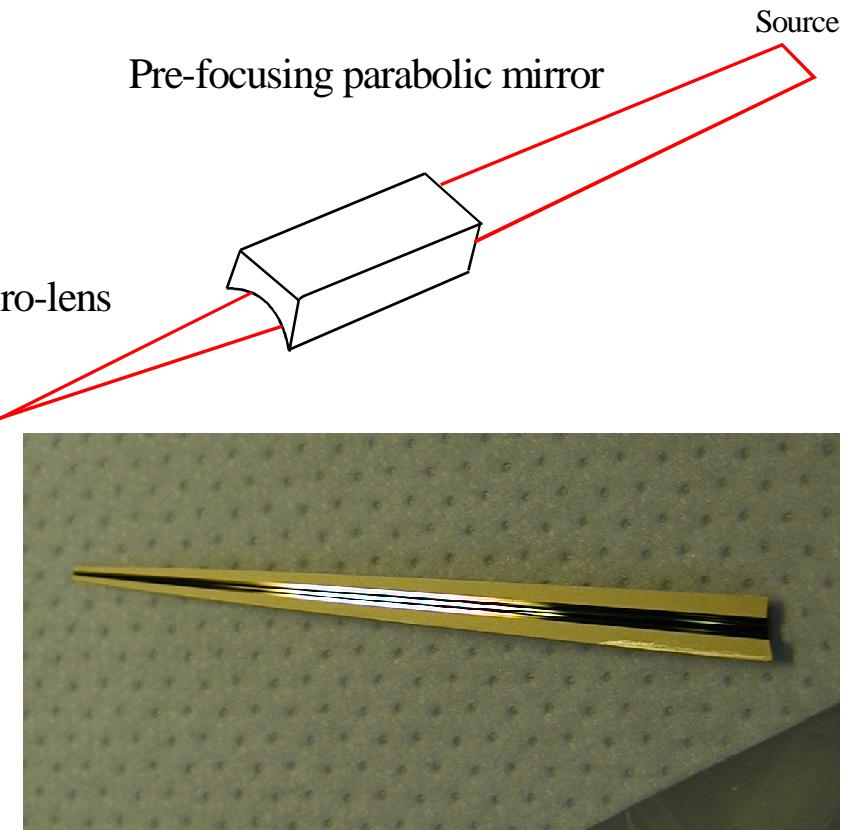
Reflection structure: Low-Energy DiS



Focal spot 100 nm possible



Off-axis Reflection Zone Plate with variable spacing. Coating: Au on Si substrate



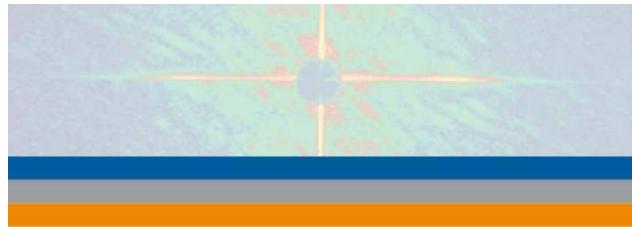
Monocapillary micro-mirror. Au coated.

Acknowledgments:



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K. Holldack, H. Dürr, C. Stamm, N. Pontius**
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W. Eberhardt





Thank you!